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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	15600
Number of Logic Elements/Cells	199680
Total RAM Bits	12681216
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vlx195t-2ff1156c

Table 2: Recommended Operating Conditions

Symbol	Description	Min	Max	Units
V_{CCINT}	Internal supply voltage relative to GND for all devices except -1L devices.	0.95	1.05	V
	For -1L commercial temperature range devices: internal supply voltage relative to GND, $T_j = 0^{\circ}\text{C}$ to $+85^{\circ}\text{C}$	0.87	0.93	V
	For -1L industrial temperature range devices: internal supply voltage relative to GND, $T_j = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$	0.91	0.97	V
V_{CCAUX}	Auxiliary supply voltage relative to GND	2.375	2.625	V
$V_{CCO}^{(1)(2)(3)}$	Supply voltage relative to GND	1.14	2.625	V
V_{IN}	2.5V supply voltage relative to GND	GND – 0.20	2.625	V
	2.5V and below supply voltage relative to GND	GND – 0.20	$V_{CCO} + 0.2$	V
$I_{IN}^{(5)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	10	mA
$V_{BATT}^{(6)}$	Battery voltage relative to GND	1.0	2.5	V
$V_{FS}^{(7)}$	External voltage supply for eFUSE programming	2.375	2.625	V
T_j	Junction temperature operating range for commercial (C) temperature devices	0	85	$^{\circ}\text{C}$
	Junction temperature operating range for extended (E) temperature devices	0	100	$^{\circ}\text{C}$
	Junction temperature operating range for industrial (I) temperature devices	–40	100	$^{\circ}\text{C}$
	Junction temperature operating range for military (M) temperature devices	–55	125	$^{\circ}\text{C}$

Notes:

1. Configuration data is retained even if V_{CCO} drops to 0V.
2. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, and 2.5V.
3. The configuration supply voltage V_{CC_CONFIG} is also known as V_{CCO_0} .
4. All voltages are relative to ground.
5. A total of 100 mA per bank should not be exceeded.
6. V_{BATT} is required only when using bitstream encryption. If battery is not used, connect V_{BATT} to either ground or V_{CCAUX} .
7. During eFUSE programming, V_{FS} must be within the recommended operating range and $T_j = +15^{\circ}\text{C}$ to $+85^{\circ}\text{C}$. Otherwise, V_{FS} can be connected to GND.

HT DC Specifications (HT_25)

Table 8: HT DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		-15	—	15	mV
V_{OCM}	Output Common Mode Voltage	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		-15	—	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		-15	—	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		-15	—	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	—	—	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.825	—	—	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: Extended LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	—	—	1.785	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.715	—	—	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	350	—	840	mV
	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High for XQ devices		350	—	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	—	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.3	1.2	2.2	V

Table 24: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTXRX}	Serial data rate	RX oversampler not enabled	0.600	–	F _{GTXMAX}	Gb/s
		RX oversampler enabled	0.480	–	0.600	Gb/s
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		–	75	–	ns
RX _{OOBVDPP}	OOB detect threshold peak-to-peak		60	–	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	0	ppm
RX _{RL}	Run length (CID)	Internal AC capacitor bypassed	–	–	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance	CDR 2 nd -order loop disabled	–200	–	200	ppm
		CDR 2 nd -order loop enabled	–2000	–	2000	ppm
SJ Jitter Tolerance ⁽²⁾						
JT_SJ _{6.5}	Sinusoidal Jitter ⁽³⁾	6.5 Gb/s	0.44	–	–	UI
JT_SJ _{5.0}	Sinusoidal Jitter ⁽³⁾	5.0 Gb/s	0.44	–	–	UI
JT_SJ _{4.25}	Sinusoidal Jitter ⁽³⁾	4.25 Gb/s	0.44	–	–	UI
JT_SJ _{3.75}	Sinusoidal Jitter ⁽³⁾	3.75 Gb/s	0.44	–	–	UI
JT_SJ _{3.125}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s	0.45	–	–	UI
JT_SJ _{3.125L}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s ⁽⁴⁾	0.45	–	–	UI
JT_SJ _{2.5}	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s ⁽⁵⁾	0.5	–	–	UI
JT_SJ _{1.25}	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s ⁽⁶⁾	0.5	–	–	UI
JT_SJ ₆₀₀	Sinusoidal Jitter ⁽³⁾	600 Mb/s	0.4	–	–	UI
JT_SJ ₄₈₀	Sinusoidal Jitter ⁽³⁾	480 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye ⁽²⁾						
JT_TJSE _{3.125}	Total Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.70	–	–	UI
		5.0 Gb/s	0.70	–	–	UI
JT_SJSE _{3.125}	Sinusoidal Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.1	–	–	UI
		5.0 Gb/s	0.1	–	–	UI

Notes:

- Using PLL_RXDIVSEL_OUT = 1, 2, and 4.
- All jitter values are based on a bit error ratio of 1e^{–12}.
- The frequency of the injected sinusoidal jitter is 80 MHz.
- PLL frequency at 1.5625 GHz and OUTDIV = 1.
- PLL frequency at 2.5 GHz and OUTDIV = 2.
- PLL frequency at 2.5 GHz and OUTDIV = 4.
- Composite jitter with RX equalizer enabled. DFE disabled.

Table 37: GTH Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
R _{XRL}	Run length (CID)		8000	–	–	UI
R _{XPPMTOL}	Data/REFCLK PPM offset tolerance		–200	–	200	ppm
SJ Jitter Tolerance ⁽¹⁾⁽²⁾⁽³⁾⁽⁴⁾						
JT_SJ _{11.18}	Sinusoidal Jitter	11.18 Gb/s	0.3	–	–	UI
JT_SJ _{10.32}	Sinusoidal Jitter	10.32 Gb/s	0.3	–	–	UI
JT_SJ _{9.95}	Sinusoidal Jitter	9.95 Gb/s	0.3	–	–	UI
JT_SJ _{2.667}	Sinusoidal Jitter	2.667 Gb/s	0.5	–	–	UI
JT_SJ _{2.48}	Sinusoidal Jitter	2.48 Gb/s	0.5	–	–	UI

Notes:

1. These values are NOT intended for protocol specific compliance determinations.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. High-frequency jitter tolerance including 6 db of channel loss at a high frequency of the data rate divided by two.

Ethernet MAC Switching Characteristics

Consult [UG368: Virtex-6 FPGA Embedded Tri-mode Ethernet MAC User Guide](#) for further information.

Table 38: Maximum Ethernet MAC Performance

Symbol	Description	Conditions	Speed Grade				Units
			-3	-2	-1	-1L	
F _{TEMACCLIENT}	Client interface maximum frequency	10 Mb/s – 8-bit width	2.5 ⁽¹⁾	2.5 ⁽¹⁾	2.5 ⁽¹⁾	2.5 ⁽¹⁾	MHz
		100 Mb/s – 8-bit width	25 ⁽²⁾	25 ⁽²⁾	25 ⁽²⁾	25 ⁽²⁾	MHz
		1000 Mb/s – 8-bit width	125	125	125	125	MHz
		1000 Mb/s – 16-bit width	62.5	62.5	62.5	62.5	MHz
		2000 Mb/s – 16-bit width	125	125	125	N/A	MHz
		2500 Mb/s – 16-bit width	156.25	156.25	156.25	N/A	MHz
F _{TEMACPHY}	Physical interface maximum frequency	10 Mb/s – 4-bit width	2.5	2.5	2.5	2.5	MHz
		100 Mb/s – 4-bit width	25	25	25	25	MHz
		1000 Mb/s – 8-bit width	125	125	125	125	MHz
		2000 Mb/s – 8-bit width	250	250	250	N/A	MHz
		2500 Mb/s – 8-bit width	312.5	312.5	312.5	N/A	MHz

Notes:

1. When not using clock enable, the F_{MAX} is lowered to 1.25 MHz.
2. When not using clock enable, the F_{MAX} is lowered to 12.5 MHz.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
AV _{DD} = 2.5V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 5.2 MHz, T _j = -55°C to 125°C M-Grade, Typical values at T _j = +35°C						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	—	—	Bits
Integral Nonlinearity	INL		—	—	±1	LSBs
Differential Nonlinearity	DNL	No missing codes (T _{MIN} to T _{MAX}) Guaranteed Monotonic	—	—	±0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	—	±2	±30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	—	±2	±30	LSBs
Gain Error		Uncalibrated - External Reference	—	±0.2	±2	%
		Uncalibrated - Internal Reference	—	±2	—	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	—	±0.2	±2	%
		Uncalibrated - Internal Reference	—	±2	—	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	—	±10	—	LSBs
		Deviation from ideal transfer function. Internal reference	—	±20	—	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	—	±1	±2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	—	±0.01	—	LSB/°C
DC Common-Mode Reject	CMRR _{DC}	V _N = V _{CM} = 0.5V ± 0.5V, V _P - V _N = 100mV	—	70	—	dB
Conversion Rate ⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	—	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	—	—	21	
T/H Acquisition Time	t _{ACQ}	Number of CLK cycles	4	—	—	
DRP Clock Frequency	DCLK	DRP clock frequency	8	—	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	—	5.2	MHz
CLK Duty cycle			40	—	60	%

Table 40: Analog-to-Digital Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
Analog Inputs ⁽³⁾						
Dedicated Analog Inputs Input Voltage Range V _P - V _N		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	20	–	MHz
Auxiliary Analog Inputs Input Voltage Range V _{AUXP[0]} /V _{AUXN[0]} to V _{AUXP[15]} /V _{AUXN[15]} T _j = –55°C to 125°C		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	10	–	kHz
Input Leakage Current		A/D not converting, ADCCLK stopped	–	±1.0	–	µA
Input Capacitance			–	10	–	pF
On-chip Supply Monitor Error		V _{CCINT} and V _{CCAUX} with calibration enabled. External 1.25V reference T _j = –55°C to 125°C.	–	–	±1.0	% Reading
		V _{CCINT} and V _{CCAUX} with calibration enabled. Internal reference T _j = –40°C to 100°C. ⁽⁴⁾	–	±2	–	% Reading
On-chip Temperature Monitor Error		T _j = –55°C to +125°C with calibration enabled. External 1.25V reference.	–	–	±4	°C
		T _j = –40°C to +100°C with calibration enabled. Internal reference. ⁽⁴⁾	–	±5	–	°C
External Reference Inputs ⁽⁵⁾						
Positive Reference Input Voltage Range	V _{REFP}	Measured Relative to V _{REFN}	1.20	1.25	1.30	Volts
Negative Reference Input Voltage Range	V _{REFN}	Measured Relative to AGND	–50	0	100	mV
Input current	I _{REF}	ADCCLK = 5.2 MHz	–	–	100	µA
Power Requirements						
Analog Power Supply	AV _{DD}	Measured Relative to AV _{SS}	2.375	2.5	2.625	Volts
Analog Supply Current	AI _{DD}	ADCCLK = 5.2 MHz	–	–	12	mA

Notes:

- Offset errors are removed by enabling the System Monitor automatic gain calibration feature.
- See "System Monitor Timing" in [UG370: Virtex-6 FPGA System Monitor User Guide](#)
- See "Analog Inputs" in [UG370: Virtex-6 FPGA System Monitor User Guide](#) for a detailed description.
- These internal references are not specified over the junction temperature operating range for military (M) temperature devices.
- Any variation in the reference voltage from the nominal $V_{REFP} = 1.25\text{V}$ and $V_{REFN} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by $\pm 4\%$ is permitted.

Switching Characteristics

All values represented in this data sheet are based on these speed specifications: v1.17 for -3, -2, and -1; and v1.10 for -1L. Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are always representative of worst-case supply voltage and junction temperature conditions.

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device.

[Table 42](#) correlates the current status of each Virtex-6 device on a per speed grade basis.

Table 42: Virtex-6 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC6VLX75T			-3, -2, -1, -1L
XC6VLX130T			-3, -2, -1, -1L
XC6VLX195T			-3, -2, -1, -1L
XC6VLX240T			-3, -2, -1, -1L
XC6VLX365T			-3, -2, -1, -1L
XC6VLX550T			-2, -1, -1L
XC6VLX760			-2, -1, -1L
XC6VSX315T			-3, -2, -1, -1L
XC6VSX475T			-2, -1, -1L
XC6VHX250T			-3, -2, -1
XC6VHX255T			-3, -2, -1
XC6VHX380T			-3, -2, -1
XC6VHX565T			-2, -1
XQ6VLX130T			-2, -1, -1L
XQ6VLX240T			-2, -1, -1L
XQ6VLX550T			-1, -1L
XQ6VSX315T			-2, -1, -1L
XQ6VSX475T			-1, -1L

Testing of Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Virtex-6 devices.

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVC MOS25, Fast, 16 mA	0.57	0.66	0.70	1.92	2.15	2.08	1.92	2.15	2.08	ns
LVC MOS25, Fast, 24 mA	0.57	0.66	0.70	1.79	2.15	1.96	1.79	2.15	1.96	ns
LVC MOS18, Slow, 2 mA	0.61	0.71	0.73	4.47	4.87	4.30	4.47	4.87	4.30	ns
LVC MOS18, Slow, 4 mA	0.61	0.71	0.73	2.96	3.21	2.94	2.96	3.21	2.94	ns
LVC MOS18, Slow, 6 mA	0.61	0.71	0.73	2.43	2.64	2.47	2.43	2.64	2.47	ns
LVC MOS18, Slow, 8 mA	0.61	0.71	0.73	2.11	2.41	2.24	2.11	2.41	2.24	ns
LVC MOS18, Slow, 12 mA	0.61	0.71	0.73	1.99	2.30	2.10	1.99	2.30	2.10	ns
LVC MOS18, Slow, 16 mA	0.61	0.71	0.73	1.95	2.30	2.04	1.95	2.30	2.04	ns
LVC MOS18, Fast, 2 mA	0.61	0.71	0.73	4.23	4.57	4.08	4.23	4.57	4.08	ns
LVC MOS18, Fast, 4 mA	0.61	0.71	0.73	2.76	2.97	2.74	2.76	2.97	2.74	ns
LVC MOS18, Fast, 6 mA	0.61	0.71	0.73	2.28	2.46	2.32	2.28	2.46	2.32	ns
LVC MOS18, Fast, 8 mA	0.61	0.71	0.73	1.99	2.34	2.14	1.99	2.34	2.14	ns
LVC MOS18, Fast, 12 mA	0.61	0.71	0.73	1.80	2.19	1.88	1.80	2.19	1.88	ns
LVC MOS18, Fast, 16 mA	0.61	0.71	0.73	1.74	2.18	1.88	1.74	2.18	1.88	ns
LVC MOS15, Slow, 2 mA	0.73	0.85	0.85	3.77	4.29	3.91	3.77	4.29	3.91	ns
LVC MOS15, Slow, 4 mA	0.73	0.85	0.85	2.79	3.10	2.93	2.79	3.10	2.93	ns
LVC MOS15, Slow, 6 mA	0.73	0.85	0.85	2.32	2.68	2.50	2.32	2.68	2.50	ns
LVC MOS15, Slow, 8 mA	0.73	0.85	0.85	1.98	2.29	2.24	1.98	2.29	2.24	ns
LVC MOS15, Slow, 12 mA	0.73	0.85	0.85	1.91	2.23	2.07	1.91	2.23	2.07	ns
LVC MOS15, Slow, 16 mA	0.73	0.85	0.85	1.83	2.23	1.98	1.83	2.23	1.98	ns
LVC MOS15, Fast, 2 mA	0.73	0.85	0.85	3.77	4.28	3.91	3.77	4.28	3.91	ns
LVC MOS15, Fast, 4 mA	0.73	0.85	0.85	2.53	2.78	2.66	2.53	2.78	2.66	ns
LVC MOS15, Fast, 6 mA	0.73	0.85	0.85	2.05	2.42	2.16	2.05	2.42	2.16	ns
LVC MOS15, Fast, 8 mA	0.73	0.85	0.85	1.90	2.20	2.04	1.90	2.20	2.04	ns
LVC MOS15, Fast, 12 mA	0.73	0.85	0.85	1.77	2.11	1.90	1.77	2.11	1.90	ns
LVC MOS15, Fast, 16 mA	0.73	0.85	0.85	1.76	2.11	1.92	1.76	2.11	1.92	ns
LVC MOS12, Slow, 2 mA	0.81	0.93	0.95	3.39	3.75	3.54	3.39	3.75	3.54	ns
LVC MOS12, Slow, 4 mA	0.81	0.93	0.95	2.63	2.93	2.79	2.63	2.93	2.79	ns
LVC MOS12, Slow, 6 mA	0.81	0.93	0.95	2.11	2.67	2.26	2.11	2.67	2.26	ns
LVC MOS12, Slow, 8 mA	0.81	0.93	0.95	2.02	2.25	2.17	2.02	2.25	2.17	ns
LVC MOS12, Fast, 2 mA	0.81	0.93	0.95	2.98	3.39	3.11	2.98	3.39	3.11	ns
LVC MOS12, Fast, 4 mA	0.81	0.93	0.95	2.16	2.70	2.31	2.16	2.70	2.31	ns
LVC MOS12, Fast, 6 mA	0.81	0.93	0.95	1.89	2.34	2.05	1.89	2.34	2.05	ns
LVC MOS12, Fast, 8 mA	0.81	0.93	0.95	1.82	2.10	1.98	1.82	2.10	1.98	ns
LVDCI_25	0.57	0.70	0.70	2.14	2.82	2.26	2.14	2.82	2.26	ns
LVDCI_18	0.61	0.71	0.73	2.23	2.78	2.38	2.23	2.78	2.38	ns
LVDCI_15	0.73	0.85	0.85	2.01	2.75	2.18	2.01	2.75	2.18	ns
LVDCI_DV2_25	0.57	0.70	0.70	1.83	2.37	2.00	1.83	2.37	2.00	ns

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 6 and Figure 7.

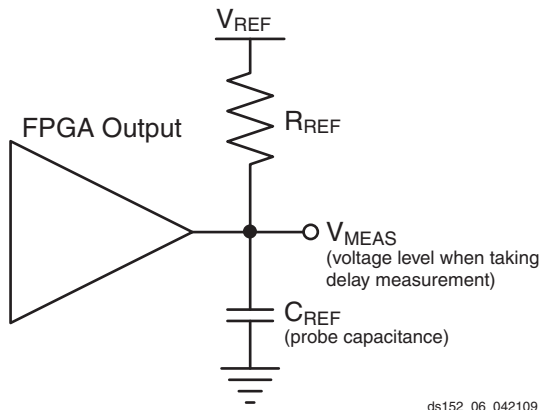
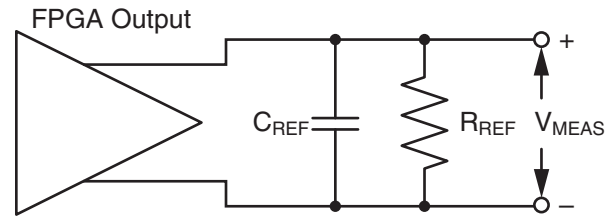


Figure 6: Single Ended Test Setup



ds152_07_042109

Figure 7: Differential Test Setup

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 48.
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 48: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R_{REF} (Ω)	$C_{REF}^{(1)}$ (pF)	V_{MEAS} (V)	V_{REF} (V)
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.2V	LVC MOS12	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25
SSTL, Class II, 2.5V	SSTL2_II	25	0	V_{REF}	1.25
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
LVDS EXT (LVDS Extended Mode), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
BLVDS (Bus LVDS), 2.5V	BLVDS_25	100	0	0 ⁽²⁾	0

Table 48: Output Delay Measurement Methodology (Cont'd)

Description	I/O Standard Attribute	R _{REF} (Ω)	C _{REF} ⁽¹⁾ (pF)	V _{MEAS} (V)	V _{REF} (V)
HT (HyperTransport), 2.5V	LDT_25	100	0	0 ⁽²⁾	0.6
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V	LVPECL_25	100	0	0 ⁽²⁾	0
LVDCI/HSLVDCI, 2.5V	LVDCI_25, HSLVDCI_25	1M	0	1.25	0
LVDCI/HSLVDCI, 1.8V	LVDCI_18, HSLVDCI_18	1M	0	0.9	0
LVDCI/HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I & II, with DCI	HSTL_I_DCI, HSTL_II_DCI	50	0	V _{REF}	0.75
HSTL, Class III, with DCI	HSTL_III_DCI	50	0	0.9	1.5
HSTL, Class I & II, 1.8V, with DCI	HSTL_I_DCI_18, HSTL_II_DCI_18	50	0	V _{REF}	0.9
HSTL, Class III, 1.8V, with DCI	HSTL_III_DCI_18	50	0	1.1	1.8
SSTL (Stub Series Termination Logic), Class I & II, 1.8V, with DCI	SSTL18_I_DCI, SSTL18_II_DCI	50	0	V _{REF}	0.9
SSTL, Class I & II, 2.5V, with DCI	SSTL2_I_DCI, SSTL2_II_DCI	50	0	V _{REF}	1.25

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 49: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Setup/Hold						
T _{ICE1CK} /T _{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.21/ 0.03	0.25/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T _{ISRCK} /T _{ICKSR}	SR pin Setup/Hold with respect to CLK	0.66/ −0.08	0.78/ −0.08	0.96/ −0.08	1.09/ −0.11	ns
T _{IDOCK} /T _{IOCKD}	D pin Setup/Hold with respect to CLK without Delay	0.07/ 0.41	0.08/ 0.46	0.10/ 0.54	0.11/ 0.64	ns
T _{IDOCKD} /T _{IOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)	0.10/ 0.32	0.12/ 0.36	0.14/ 0.42	0.16/ 0.50	ns
Combinatorial						
T _{IDI}	D pin to O pin propagation delay, no Delay	0.15	0.17	0.20	0.23	ns
T _{IDID}	DDLY pin to O pin propagation delay (using IODELAY)	0.19	0.22	0.25	0.28	ns
Sequential Delays						
T _{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.48	0.54	0.64	0.73	ns
T _{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY)	0.52	0.58	0.68	0.78	ns
T _{ICKQ}	CLK to Q outputs	0.54	0.61	0.70	0.93	ns
T _{RQ_ILOGIC}	SR pin to OQ/TQ out	0.85	0.97	1.15	1.32	ns
T _{GSRQ_ILOGIC}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	ns
Set/Reset						
T _{RPW_ILOGIC}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.30	ns, Min

Table 50: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{ODCK} /T _{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/ −0.08	0.50/ −0.08	0.54/ −0.08	0.54/ −0.08	0.69/ −0.11	ns
T _{OOCECK} /T _{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.17/ −0.03	0.20/ −0.03	0.22/ −0.03	0.27/ −0.05	0.27/ −0.04	ns
T _{OSRCK} /T _{OCKSR}	SR pin Setup/Hold with respect to CLK	0.59/ −0.24	0.62/ −0.24	0.54/ −0.08	0.54/ −0.08	0.79/ −0.35	ns
T _{OTCK} /T _{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.44/ −0.07	0.51/ −0.07	0.56/ −0.07	0.60/ −0.10	0.68/ −0.13	ns
T _{OTCECK} /T _{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.15/ −0.04	0.19/ −0.04	0.21/ −0.04	0.27/ −0.05	0.29/ −0.05	ns
Combinatorial							
T _{DOQ}	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
Sequential Delays							
T _{OCKQ}	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T _{RQ}	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T _{GSRQ}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
Set/Reset							
T _{RPW}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Input/Output Delay Switching Characteristics

Table 53: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3.00	3.00	3.00	3.25	μs
F _{IDELAYCTRL_REF}	REFCLK frequency = 200.0 ⁽¹⁾	200	200	200	200	MHz
	REFCLK frequency = 300.0 ⁽¹⁾	300	300	–	–	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	50.00	50.00	50.00	52.50	ns
IODELAY						
T _{IDELAYRESOLUTION}	IODELAY Chain Delay Resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IODELAY_CLK_MAX}	Maximum frequency of CLK input to IODELAY	500.00	420.00	300.00	300.00	MHz
T _{IODCCK_CE} / T _{IODCKC_CE}	CE pin Setup/Hold with respect to CK	0.45/ –0.09	0.53/ –0.09	0.65/ –0.09	0.84/ –0.14	ns
T _{IODCK_INC} / T _{IODCKC_INC}	INC pin Setup/Hold with respect to CK	0.23/ –0.02	0.27/ –0.01	0.31/ 0.00	0.27/ –0.04	ns
T _{IODCCK_RST} / T _{IODCKC_RST}	RST pin Setup/Hold with respect to CK	0.57/ –0.08	0.62/ –0.08	0.69/ –0.08	0.74/ –0.13	ns
T _{IODDO_T}	TSCONTROL delay to MUXE/MUXF switching and through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_IDATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_ODATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY tap setting. See TRACE report for actual values.

CLB Switching Characteristics

Table 54: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Combinatorial Delays						
T _{ILO}	An – Dn LUT address to A	0.06	0.07	0.07	0.09	ns, Max
	An – Dn LUT address to AMUX/CMUX	0.18	0.20	0.22	0.25	ns, Max
	An – Dn LUT address to BMUX_A	0.28	0.31	0.36	0.40	ns, Max

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 55: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.92	1.10	1.36	1.49	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	1.19	1.40	1.71	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS} /T _{DH}	A – D inputs to CLK	0.62/0.18	0.72/0.20	0.88/0.22	0.98/0.23	ns, Min
T _{AS} /T _{AH}	Address An inputs to clock	0.19/0.52	0.22/0.59	0.27/0.66	0.30/0.75	ns, Min
T _{WS} /T _{WH}	WE input to clock	0.27/0.00	0.32/0.00	0.40/0.00	0.47/–0.03	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK	0.28/–0.01	0.34/–0.01	0.41/–0.01	0.48/–0.05	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.70	0.82	1.00	1.04	ns, Min
T _{MCP}	Minimum clock period	1.40	1.64	2.00	2.08	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 56: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.11	1.30	1.58	1.74	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.37	1.60	1.93	2.12	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	1.08	1.27	1.55	1.74	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS} /T _{WH}	WE input	0.05/0.00	0.07/0.00	0.09/0.00	0.11/0.03	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK	0.06/–0.01	0.08/–0.01	0.10/–0.01	0.12/0.02	ns, Min
T _{DS} /T _{DH}	A – D inputs to CLK	0.64/0.18	0.76/0.21	0.94/0.24	1.07/0.23	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.60	0.70	0.85	0.89	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

Block RAM and FIFO Switching Characteristics

Table 57: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.60	1.79	2.08	2.36	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.60	0.66	0.75	0.83	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.62	2.89	3.30	3.73	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.71	0.77	0.86	0.94	ns, Max
T _{RCKO_CASC} and T _{RCKO_CASC_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.49	2.77	3.18	3.61	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	1.29	1.41	1.58	1.79	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.74	0.81	0.91	0.98	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.90	0.98	1.09	1.21	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (with output register)	0.62	0.68	0.76	0.82	ns, Max
	Clock CLK to BITERR (without output register)	2.21	2.46	2.84	3.23	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.86	0.94	1.06	1.18	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.73	0.79	0.90	1.00	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.76	0.82	0.92	1.02	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDR} /T _{RCKC_ADDR}	ADDR inputs ⁽⁸⁾	0.47/ 0.27	0.53/ 0.29	0.62/ 0.32	0.66/ 0.34	ns, Min
T _{RDCK_DI} /T _{RCKD_DI}	DIN inputs ⁽⁹⁾	0.84/ 0.30	0.95/ 0.32	1.11/ 0.34	1.26/ 0.36	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.47/ 0.30	0.52/ 0.32	0.59/ 0.34	0.68/ 0.36	ns, Min
	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.68/ 0.30	0.75/ 0.32	0.85/ 0.34	0.97/ 0.36	ns, Min
	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.77/ 0.30	0.87/ 0.32	1.02/ 0.34	1.16/ 0.36	ns, Min
T _{RCKC_CLK} /T _{RCKC_CLK}	Inject single/double bit error in ECC mode	0.90/ 0.27	1.02/ 0.28	1.20/ 0.29	1.56/ 0.29	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	Block RAM Enable (EN) input	0.31/ 0.26	0.35/ 0.27	0.41/ 0.30	0.44/ 0.31	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.18/ 0.25	0.19/ 0.27	0.22/ 0.31	0.24/ 0.33	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/ 0.23	0.36/ 0.24	0.41/ 0.27	0.46/ 0.29	ns, Min

DSP48E1 Switching Characteristics

Table 58: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}; B, \text{BCIN}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}; B, \text{BCIN}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{\text{DSPDCK}_{\text{C_CREG}}/T_{\text{DSPCKD}_{\text{C_CREG}}}}$	C input to C register CLK	0.16/ 0.20	0.19/ 0.22	0.22/ 0.24	0.25/ 0.24	0.33/ 0.30	ns
$T_{\text{DSPDCK}_{\text{D_DREG}}/T_{\text{DSPCKD}_{\text{D_DREG}}}}$	D input to D register CLK	0.07/ 0.31	0.10/ 0.34	0.15/ 0.39	0.16/ 0.39	0.24/ 0.45	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{MREG_MULT}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{MREG_MULT}}}$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{\text{DSPDCK}_{\{A, D\}}_{\text{ADREG}}/T_{\text{DSPCKD}_{\{A, D\}}_{\text{ADREG}}}$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG_MULT}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG_MULT}}}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ −0.13	4.37/ −0.13	5.20/ −0.13	5.20/ −0.13	5.94/ −0.24	ns
$T_{\text{DSPDCK}_{\text{D_PREG_MULT}}/T_{\text{DSPCKD}_{\text{D_PREG_MULT}}}}$	D input to P register CLK	3.62/ −0.47	4.13/ −0.47	4.90/ −0.47	4.90/ −0.47	5.61/ −0.77	ns
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG}}}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ −0.13	1.81/ −0.13	2.15/ −0.13	2.15/ −0.13	2.44/ −0.24	ns
$T_{\text{DSPDCK}_{\text{C_PREG}}/T_{\text{DSPCKD}_{\text{C_PREG}}}}$	C input to P register CLK	1.42/ −0.10	1.61/ −0.10	1.91/ −0.10	1.91/ −0.10	2.16/ −0.19	ns
$T_{\text{DSPDCK}_{\{\text{PCIN}, \text{CARRYCASCIN}, \text{MULTSIGNIN}\}}_{\text{PREG}}/T_{\text{DSPCKD}_{\{\text{PCIN}, \text{CARRYCASCIN}, \text{MULTSIGNIN}\}}_{\text{PREG}}}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ −0.02	1.41/ −0.02	1.67/ −0.02	1.67/ −0.02	1.91/ −0.07	ns
Setup and Hold Times of the CE Pins							
$T_{\text{DSPDCK}_{\{\text{CEA}; \text{CEB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{CEA}; \text{CEB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{\text{DSPDCK}_{\text{CEC_CREG}}/T_{\text{DSPCKD}_{\text{CEC_CREG}}}}$	CEC input to C register CLK	0.15/ 0.18	0.18/ 0.20	0.24/ 0.23	0.24/ 0.23	0.31/ 0.26	ns
$T_{\text{DSPDCK}_{\text{CED_DREG}}/T_{\text{DSPCKD}_{\text{CED_DREG}}}}$	CED input to D register CLK	0.20/ 0.12	0.24/ 0.13	0.31/ 0.14	0.31/ 0.14	0.43/ 0.16	ns
$T_{\text{DSPDCK}_{\text{CEM_MREG}}/T_{\text{DSPCKD}_{\text{CEM_MREG}}}}$	CEM input to M register CLK	0.16/ 0.19	0.20/ 0.21	0.26/ 0.25	0.26/ 0.25	0.32/ 0.28	ns
$T_{\text{DSPDCK}_{\text{CEP_PREG}}/T_{\text{DSPCKD}_{\text{CEP_PREG}}}}$	CEP input to P register CLK	0.32/ 0.02	0.38/ 0.02	0.46/ 0.03	0.46/ 0.03	0.54/ 0.04	ns
Setup and Hold Times of the RST Pins							
$T_{\text{DSPDCK}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{\text{DSPDCK}_{\text{RSTC_CREG}}/T_{\text{DSPCKD}_{\text{RSTC_CREG}}}}$	RSTC input to C register CLK	0.18/ 0.08	0.20/ 0.08	0.23/ 0.09	0.23/ 0.09	0.27/ 0.11	ns
$T_{\text{DSPDCK}_{\text{RSTD_DREG}}/T_{\text{DSPCKD}_{\text{RSTD_DREG}}}}$	RSTD input to D register CLK	0.28/ 0.15	0.32/ 0.16	0.38/ 0.19	0.38/ 0.19	0.45/ 0.21	ns
$T_{\text{DSPDCK}_{\text{RSTM_MREG}}/T_{\text{DSPCKD}_{\text{RSTM_MREG}}}}$	RSTM input to M register CLK	0.20/ 0.24	0.23/ 0.26	0.26/ 0.30	0.26/ 0.30	0.29/ 0.34	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Maximum Frequency							
F _{MAX}	With all registers used	600	540	450	450	410	MHz
F _{MAX_PATDET}	With pattern detector	551	483	408	408	356	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	356	311	262	262	224	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	327	286	241	241	211	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	398	347	292	292	254	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	398	347	292	292	254	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	266	233	196	196	171	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	250	219	184	184	160	MHz

Configuration Switching Characteristics

Table 59: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program Latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on-Reset	15/55	15/55	15/55	15/60	ms, Min/Max
T _{ICCK}	CCLK (output) delay	400	400	400	400	ns, Min
T _{PROGRAM}	Program Pulse Width	250	250	250	250	ns, Min
Master/Slave Serial Mode Programming Switching						
T _{DCCK} /T _{CCKD}	DIN Setup/Hold, slave mode	4.0/0.0	4.0/0.0	4.0/0.0	4.5/0.0	ns, Min
T _{DSCCK} /T _{SCCKD}	DIN Setup/Hold, master mode	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns, Min
T _{CCO}	DOUT at 2.5V	6	6	6	7	ns, Max
	DOUT at 1.8V	6	6	6	7	ns, Max
F _{MCCK}	Maximum CCLK frequency, serial modes	105	105	105	70	MHz, Max
F _{MCCKTOL}	Frequency Tolerance, master mode with respect to nominal CCLK.	55	55	55	60	%
F _{MSCCK}	Slave mode external CCLK	100	100	100	100	MHz
SelectMAP Mode Programming Switching						
T _{SMDCCK} /T _{SMCCKD}	SelectMAP Data Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCSCCK} /T _{SMCCKCS}	CSI_B Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCCKW} /T _{SMWCCK}	RDWR_B Setup/Hold	10.0/0.0	10.0/0.0	10.0/0.0	16.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	6	6	6	7	ns, Max
T _{SMCO}	CCLK to DATA out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to DATA out in readback at 1.8V	6	6	6	7	ns, Max

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
F _{SMCK}	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
F _{RBCK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
Boundary-Scan Port Timing Specifications						
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
F _{TCK}	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
F _{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
F _{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
BPI Master Flash Mode Programming Switching						
T _{BPICCO} ⁽²⁾	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
T _{BPIDCC} /T _{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
T _{INITADDR}	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching						
T _{SPIDCC} /T _{SPIDCCD}	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
T _{SPICCM}	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
T _{SPICFC}	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
T _{FSINIT} /T _{FSINITH}	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	µs
CCLK Output (Master Modes)						
T _{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
F _{DCK}	Maximum frequency for DCLK	200	200	200	200	MHz
T _{MMCMCDCK_DADDR} / T _{MMCMCKD_DADDR}	DADDR Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns

Table 64: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
RST _{MINPULSE}	Minimum Reset Pulse Width	1.5	1.5	1.5	1.5	ns
F _{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized ⁽⁹⁾	550	500	450	450	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300	300	300	300	MHz
F _{PFDMIN}	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	135	135	135	135	MHz
	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	10	10	10	10	MHz
T _{FBDELAY}	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
T _{MMCMCK_PSEN} / T _{MMCMCKD_PSEN}	Setup and Hold of Phase Shift Enable	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMCK_PINCDEC} / T _{MMCMCKD_PINCDEC}	Setup and Hold of Phase Shift Increment/Decrement	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMCKO_PSDONE}	Phase Shift Clock-to-Out of PSDONE	0.32	0.34	0.38	0.38	ns

Notes:

1. When DIVCLK_DIVIDE = 3 or 4, F_{INMAX} is 315 MHz.
2. This duty cycle specification does not apply to the GTH_QUAD (GTH) to MMCM connection. The GTH transceivers drive the MMCMs at the following maximum frequencies: 323 MHz for -1 speed grade devices, 350 MHz for -2 speed grade devices, or 350 MHz for -3 speed grade devices.
3. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
4. The static offset is measured between any MMCM outputs with identical phase.
5. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
6. Includes global clock buffer.
7. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.
8. When CASCADE4_OUT = TRUE, F_{OUTMIN} is 0.036 MHz.
9. In ISE software 12.3 (or earlier versions supporting the Virtex-6 family), the phase frequency detector Optimized bandwidth setting is equivalent to the High bandwidth setting. Starting with ISE software 12.4, the Optimized bandwidth setting is automatically adjusted to Low when the software can determine that the phase frequency detector input is less than 135 MHz.

Virtex-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 68. Values are expressed in nanoseconds unless otherwise noted.

Table 68: Global Clock Input Setup and Hold Without MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSFD} / T _{PHFD}	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF ⁽²⁾ without MMCM	XC6VLX75T	1.33/ 0.03	1.44/ 0.03	1.75/ 0.03	2.18/ −0.22	ns
		XC6VLX130T	1.31/ −0.08	1.54/ −0.08	1.88/ −0.08	2.31/ −0.12	ns
		XC6VLX195T	1.36/ −0.11	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XC6VLX240T	1.36/ −0.11	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XC6VLX365T	1.79/ −0.28	1.87/ −0.28	2.17/ −0.28	2.48/ −0.24	ns
		XC6VLX550T	N/A	2.22/ −0.12	2.36/ −0.12	2.77/ −0.26	ns
		XC6VLX760	N/A	2.19/ −0.24	2.35/ −0.24	2.71/ −0.21	ns
		XC6VSX315T	1.75/ −0.09	1.85/ −0.09	2.06/ −0.09	2.47/ −0.24	ns
		XC6VSX475T	N/A	2.14/ −0.14	2.31/ −0.14	2.71/ −0.30	ns
		XC6VHX250T	1.93/ −0.22	2.04/ −0.22	2.25/ −0.22	N/A	ns
		XC6VHX255T	1.81/ −0.33	2.11/ −0.33	2.56/ −0.33	N/A	ns
		XC6VHX380T	1.93/ −0.11	2.04/ −0.11	2.25/ −0.11	N/A	ns
		XC6VHX565T	N/A	2.20/ −0.12	2.39/ −0.12	N/A	ns
		XQ6VLX130T	N/A	1.54/ −0.08	1.88/ −0.08	2.31/ −0.12	ns
		XQ6VLX240T	N/A	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XQ6VLX550T	N/A	N/A	2.36/ −0.12	2.77/ −0.26	ns
		XQ6VSX315T	N/A	1.85/ −0.09	2.06/ −0.09	2.47/ −0.24	ns
		XQ6VSX475T	N/A	N/A	2.31/ −0.14	2.71/ −0.30	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Table 73: Sample Window

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	All	510	560	610	670	ps
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO ⁽²⁾	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: Pin-to-Pin Setup/Hold and Clock-to-Out

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO						
T _{PSCS} /T _{PHCS}	Setup/Hold of I/O clock	−0.28/1.09	−0.28/1.16	−0.28/1.33	−0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFIO						
T _{ICKOFC}	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V_{CCAUX} and V_{IN} numbers in Table 2, page 2 . Removed empty column from Table 3, page 3 . Revised specifications on Table 20, page 13 . Updated Table 38, page 22 and added notes 1 and 2. Revised T_{DLYCCO_RDY} , $T_{IDELAYCTRL_RPW}$, and $T_{IDELAYPAT_JIT}$ in Table 53, page 41 . Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T_{TAPTCK}/T_{TCKTAP} in Table 59, page 49 . Updated XC6VLX130T parameters in Table 68 through Table 70, page 59 .
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V_{FS} and notes to Table 1 and Table 2 . Removed DV_{PPIN} from the example in Figure 2 . Added networking applications to Table 41, page 25 . Changed and added to the block RAM F_{MAX} section in Table 57, page 44 including removing Note 12. Changed F_{PFDMAX} values and corrected units for $T_{STATPHAOFFSET}$ and $T_{OUTDUTY}$ in Table 64, page 52 . Updated Table 71, page 60 .
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications . Updated speed specifications as described in Switching Characteristics , includes changes in Table 51 , Table 57 , Table 58 , and Table 66 through Table 70 . Comprehensive changes to Table 14 , Table 15 , and Table 16 . Added conditions to DV_{PPOUT} and revised description of T_{OSKEW} in Table 17 . Removed V_{ISE} specification and note from Table 18 . Added note 3 to Table 23 . Updated note 3 in Table 24 . Updated LVCMOS25 delays in Table 44 . Updated specification for T_{IOTPHZ} in Table 46 . Removed $T_{BUFHSKEW}$ from Table 71, page 60 and added values for $T_{BUFIOSKEW}$. Added values in Table 74 .